



CERTIFICATE OF ACCREDITATION

The ANSI National Accreditation Board

Hereby attests that

Transcat-Phoenix
8240 S. Kyrene Road, Suite 107
Tempe, AZ 85284

Fulfills the requirements of

ISO/IEC 17025:2017

and the national standards

**ANSI/NCSL Z540-1-1994 (R2002) AND
ANSI/NCSL Z540.3-2006 (R2013)**

In the fields of

CALIBRATION AND DIMENSIONAL MEASUREMENT

This certificate is valid only when accompanied by a current scope of accreditation document.
The current scope of accreditation can be verified at www.anab.org.

Jason Stine, Vice President

Expiry Date: 07 September 2027
Certificate Number: AC-2489.11



This laboratory is accredited in accordance with the recognized International Standard ISO/IEC 17025:2017.
This accreditation demonstrates technical competence for a defined scope and the operation of a laboratory
quality management system (refer to joint ISO-ILAC-IAF Communiqué dated April 2017).

SCOPE OF ACCREDITATION TO ISO/IEC 17025:2017

AND

ANSI/NCSL Z540-1-1994 (R2002)

ANSI/NCSL Z540.3-2006 (R2013)

Transcat – Phoenix

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CALIBRATION AND DIMENSIONAL MEASUREMENT

ISO/IEC 17025 Accreditation Granted: **24 July 2025**

Certificate Number: **AC-2489.11**

Certificate Expiry Date: **07 September 2027**

CALIBRATION

Electrical – DC/Low Frequency

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
Sine Wave Flatness ¹ (into 50 Ω load)	(0.3 to 1) V 10 Hz to 1 MHz (1 to 10) MHz (10 to 30) MHz (30 to 50) MHz (50 to 80) MHz (80 to 100) MHz	0.073 % of reading 0.11 % of reading 0.3 % of reading 0.66 % of reading 1.5 % of reading 2.4 % of reading	Comparison to Agilent 11050A Thermal Convertor
Sine Wave Flatness ¹ (into 50 Ω load)	(1 to 3) V 10 Hz to 1 MHz (1 to 10) MHz (10 to 30) MHz (30 to 50) MHz (50 to 80) MHz (80 to 100) MHz	0.071 % of reading 0.086 % of reading 0.17 % of reading 0.35 % of reading 0.85 % of reading 1.3 % of reading	Comparison to Agilent 11049A Thermal Convertor
AC Current – Source ¹	Up to 220 μ A (10 to 20) Hz (20 to 40) Hz 40 Hz to 1 kHz (1 to 5) kHz (5 to 10) kHz	0.025 % of reading + 16 nA 0.016 % of reading + 10 nA 0.011 % of reading + 8 nA 0.028 % of reading + 12 nA 0.11 % of reading + 65 nA	Comparison to Fluke 5730A Multiproduct Calibrator

This Scope of Accreditation, version 015, was last updated on: 25 June 2026 and is valid only when accompanied by the Certificate.

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Electrical – DC/Low Frequency

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
AC Current – Source ¹	(0.22 to 2.2) mA		Comparison to Fluke 5730A Multiproduct Calibrator
	(10 to 20) Hz	0.025 % of reading + 40 nA	
	(20 to 40) Hz	0.016 % of reading + 35 nA	
	40 Hz to 1 kHz	0.011 % of reading + 35 nA	
	(1 to 5) kHz	0.028 % of reading + 0.11 µA	
	(5 to 10) kHz	0.11 % of reading + 0.65 µA	
	(2.2 to 22) mA		
	(10 to 20) Hz	0.025 % of reading + 0.4 µA	
	(20 to 40) Hz	0.016 % of reading + 0.35 µA	
	40 Hz to 1 kHz	0.011 % of reading + 0.35 µA	
	(1 to 5) kHz	0.02 % of reading + 0.55 µA	
	(5 to 10) kHz	0.11 % of reading + 5 µA	
AC Current – Source ¹	(22 to 220) mA		Comparison to Fluke 5730A Multiproduct Calibrator
	(10 to 20) Hz	0.025 % of reading + 4 µA	
	(20 to 40) Hz	0.016 % of reading + 3.5 µA	
	40 Hz to 1 kHz	0.011 % of reading + 2.5 µA	
	(1 to 5) kHz	0.02 % of reading + 3.5 µA	
	(5 to 10) kHz	0.11 % of reading + 10 µA	
AC Current – Source ¹	(0.22 to 2.2) A		Comparison to Fluke 5730A Multiproduct Calibrator, Fluke 5725A Amplifier
	20 Hz to 1 kHz	0.025 % of reading + 35 µA	
	(1 to 5) kHz	0.045 % of reading + 80 µA	
	(5 to 10) kHz	0.7 % of reading + 0.16 mA	
AC Current – Source ¹	(2.2 to 11) A		Comparison to Fluke 5730A Multiproduct Calibrator, Fluke 5725A Amplifier
	40 Hz to 1 kHz	0.046 % of reading + 0.17 mA	
	(1 to 5) kHz	0.095 % of reading + 0.38 mA	
	(5 to 10) kHz	0.36 % of reading + 0.75 mA	
AC Current – Source ¹	(11 to 20.5) A		Comparison to Fluke 5520A Multiproduct Calibrator
	(45 to 100) Hz	0.095 % of reading + 4 mA	
	100 Hz to 1 kHz	0.12 % of reading + 4 mA	
	(1 to 5) kHz	2.3 % of reading + 4 mA	
AC Current – Source ¹ (Extended Frequency Ranges)	(29 to 330) µA		Comparison to Fluke 5520A Multiproduct Calibrator
	(10 to 30) kHz	1.2 % of reading + 0.31 µA	
	(0.33 to 3.3) mA		
	(10 to 30) kHz	0.78 % of reading + 0.47 µA	
	(3.3 to 33) mA		
	10 kHz to 30 kHz	0.31 % of reading + 3.1 µA	
AC Current – Source ¹ (Extended Frequency Ranges)	(33 to 330) mA		Comparison to Fluke 5520A Multiproduct Calibrator
	(10 to 30) kHz	0.31 % of reading + 0.16 mA	

Electrical – DC/Low Frequency

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
AC Clamp-on Ammeters ¹ (Toroidal Type) Transformer Type Sensor	(20 to 150) A (45 to 65) Hz (65 to 440) Hz (150 to 1 000) A (45 to 65) Hz (65 to 440) Hz	0.35 % of reading + 30 mA 0.94 % of reading + 50 mA 0.34 % of reading + 0.13 A 1.2 % of reading + 0.23 A	Comparison to Fluke 5520A Multiproduct Calibrator, Fluke 5500A/COIL 50-turn Coil
AC Clamp-on Ammeters ¹ (Non-Toroidal Type) Hall Effect Sensor	(20 to 150) A (45 to 65) Hz (65 to 440) Hz (150 to 1 000) A (45 to 65) Hz (65 to 440) Hz	0.68 % of reading + 0.29 A 1.2 % of reading + 0.29 A 0.66 % of reading + 1 A 1.4 % of reading + 1.1 A	Comparison to Fluke 5520A Multiproduct Calibrator, Fluke 5500A/COIL 50-turn Coil
AC Current – Measure ¹	Up to 100 μ A (10 to 20) Hz (20 to 45) Hz (45 to 100) Hz 100 Hz to 1 kHz (0.1 to 1) mA (10 to 20) Hz (20 to 45) Hz (45 to 100) Hz 100 Hz to 5 kHz (1 to 10) mA (10 to 20) Hz (20 to 45) Hz (45 to 100) Hz 100 Hz to 5 kHz (10 to 100) mA (10 to 20) Hz (20 to 45) Hz (45 to 100) Hz 100 Hz to 5 kHz 100 mA to 1 A (10 to 20) Hz (20 to 45) Hz (45 to 100) Hz 100 Hz to 5 kHz	0.4 % of reading + 30 nA 0.17 % of reading + 30 nA 0.072 % of reading + 30 nA 0.072 % of reading + 30 nA 0.4 % of reading + 0.2 μ A 0.15 % of reading + 0.2 μ A 0.062 % of reading + 0.2 μ A 0.034 % of reading + 0.2 μ A 0.4 % of reading + 2 μ A 0.15 % of reading + 2 μ A 0.062 % of reading + 2 μ A 0.034 % of reading + 2 μ A 0.4 % of reading + 20 μ A 0.15 % of reading + 20 μ A 0.062 % of reading + 20 μ A 0.034 % of reading + 20 μ A 0.4 % of reading + 0.2 mA 0.16 % of reading + 0.2 mA 0.087 % of reading + 0.2 mA 0.14 % of reading + 0.2 mA	Comparison to Agilent 3458A opt 002 8.5 Digit Multimeter

Electrical – DC/Low Frequency

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
AC Current – Measure ¹	(1 to 30) A (50 to 100) Hz (100 to 300) Hz 300 Hz to 1 kHz (1 to 3) kHz (3 to 4) kHz (4 to 5) kHz	0.065 % of reading + 0.23 mA 0.065 % of reading + 0.23 mA 0.065 % of reading + 0.23 mA 0.37 % of reading + 0.23 mA 0.37 % of reading + 0.23 mA 0.37 % of reading + 0.23 mA	Comparison to Agilent 34330A Current Shunt, Agilent 3458A opt 002 8.5 Digit Multimeter
DC Current – Source ¹	(0.2 to 220) μ A (0.2 to 2.2) mA (2.2 to 22) mA (22 to 220) mA (0.22 to 2.2) A	40 μ A/A + 6 nA 35 μ A/A + 7 nA 35 μ A/A + 40 nA 45 μ A/A + 0.7 μ A 80 μ A/A + 12 μ A	Comparison to Fluke 5730A Multiproduct Calibrator
DC Current – Source ¹	(2.2 to 11) A	0.036 % of reading + 0.48 mA	Comparison to Fluke 5730A Multiproduct Calibrator, Fluke 5725A Amplifier
DC Current – Source/Measure ¹	Up to 100 μ A (0.1 to 1) mA (1 to 10) mA (10 to 100) mA (0.1 to 1) A	33 μ A/A + 0.92 nA 29 μ A/A + 5.8 nA 29 μ A/A + 58 nA 46 μ A/A + 0.58 μ A 0.013 % of reading + 12 μ A	Comparison to Agilent 3458A opt 002 8.5 Digit Multimeter, Current Source
DC Current – Source/Measure ¹	(1 to 20) A	0.45 mA/A	Comparison to Agilent 34330A Current Shunt, Agilent 3458A opt 002 8.5 Digit Multimeter, DC Current Source
DC Clamp-on Ammeters ¹ (Non-Toroidal Type) Hall Effect Sensor	(20 to 150) A (150 to 1 000) A	0.53 % of reading + 0.17 A 0.52 % of reading + 0.58 A	Comparison to Fluke 5520A Multiproduct Calibrator, Fluke 5500A/COIL 50-turn Coil
DC Current – Measure ¹	(20 to 100) A	0.046 % of reading	Comparison to L&N 4361 Current Shunt, Agilent 3458A opt 002 8.5 Digit Multimeter

Electrical – DC/Low Frequency

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
DC Resistance – Measure ¹	Up to 10 Ω (10 to 100) Ω (0.1 to 1) k Ω (1 to 10) k Ω (10 to 100) k Ω (0.1 to 1) M Ω (1 to 10) M Ω (10 to 100) M Ω (0.1 to 1) G Ω	16 $\mu\Omega/\Omega$ + 50 $\mu\Omega$ 14 $\mu\Omega/\Omega$ + 0.5 m Ω 12 $\mu\Omega/\Omega$ + 0.5 m Ω 13 $\mu\Omega/\Omega$ + 5 m Ω 13 $\mu\Omega/\Omega$ + 50 m Ω 17 $\mu\Omega/\Omega$ + 2 Ω 58 $\mu\Omega/\Omega$ + 0.1 k Ω 0.052 % of reading + 1 k Ω 0.5 % of reading + 10 k Ω	Comparison to Agilent 3458A opt 002 8.5 Digit Multimeter
DC Resistance – Source/Measure ¹	Up to 10 Ω (10 to 100) Ω (0.1 to 1) k Ω (1 to 10) k Ω (10 to 100) k Ω (0.1 to 1) M Ω (1 to 10) M Ω (10 to 100) M Ω (0.1 to 1) G Ω	18 $\mu\Omega/\Omega$ + 58 $\mu\Omega$ 15 $\mu\Omega/\Omega$ + 0.58 m Ω 13 $\mu\Omega/\Omega$ + 0.58 m Ω 12 $\mu\Omega/\Omega$ + 5.8 m Ω 13 $\mu\Omega/\Omega$ + 58 m Ω 21 $\mu\Omega/\Omega$ + 2.3 Ω 62 $\mu\Omega/\Omega$ + 0.12 k Ω 0.059 % of reading + 1.2 k Ω 0.82 % of reading + 12 k Ω	Comparison to Agilent 3458A opt 002 8.5 Digit Multimeter, characterized with Decade Resistor
DC Resistance – Source/Measure ¹	(10 to 100) M Ω (0.1 to 1) G Ω (1 to 10) G Ω (10 to 100) G Ω (100 to 300) G Ω (300 to 700) G Ω (0.7 to 1) T Ω	0.012 % of reading + 0.28 k Ω 0.012 % of reading + 9.7 k Ω 0.012 % of reading + 0.42 M Ω 0.012 % of reading + 45 M Ω 0.016 % of reading + 45 M Ω 0.016 % of reading + 0.11 G Ω 0.016 % of reading + 0.49 G Ω	Comparison to Extended Arm Bridge
DC Resistance – Source ¹ (Fixed Artifacts)	10 $\mu\Omega$ 100 $\mu\Omega$ 1 m Ω 10 m Ω 100 m Ω	0.4 % of reading 0.046 % of reading 0.046 % of reading 35 $\mu\Omega/\Omega$ 67 $\mu\Omega/\Omega$	Comparison to Standard Resistors

Electrical – DC/Low Frequency

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
DC Resistance – Source ^{1,6} (Simulation)	0 Ω	40 $\mu\Omega$	Comparison to Fluke 5730A Multiproduct Calibrator
	1 Ω	95 $\mu\Omega/\Omega$	
	1.9 Ω	95 $\mu\Omega/\Omega$	
	10 Ω	23 $\mu\Omega/\Omega$	
	19 Ω	23 $\mu\Omega/\Omega$	
	100 Ω	10 $\mu\Omega/\Omega$	
	190 Ω	10 $\mu\Omega/\Omega$	
	1 k Ω	6.5 $\mu\Omega/\Omega$	
	1.9 k Ω	6.5 $\mu\Omega/\Omega$	
	10 k Ω	6.5 $\mu\Omega/\Omega$	
	19 k Ω	6.5 $\mu\Omega/\Omega$	
	100 k Ω	8.5 $\mu\Omega/\Omega$	
	190 k Ω	8.5 $\mu\Omega/\Omega$	
	1 M Ω	13 $\mu\Omega/\Omega$	
	1.9 M Ω	18 $\mu\Omega/\Omega$	
	10 M Ω	40 $\mu\Omega/\Omega$	
	19 M Ω	47 $\mu\Omega/\Omega$	
	100 M Ω	0.11 m Ω/Ω	
AC Voltage – Source ¹	Up to 2.2 mV		Comparison to Fluke 5730A Multiproduct Calibrator
	(10 to 20) Hz	0.024 % of reading + 4 μV	
	(20 to 40) Hz	0.009 % of reading + 4 μV	
	40 Hz to 20 kHz	0.008 % of reading + 4 μV	
	(20 to 50) kHz	0.02 % of reading + 4 μV	
	(50 to 100) kHz	0.05 % of reading + 5 μV	
	(100 to 300) kHz	0.11 % of reading + 10 μV	
	(300 to 500) kHz	0.14 % of reading + 20 μV	
	500 kHz to 1 MHz	0.27 % of reading + 20 μV	
	(2.2 to 22) mV		
	(10 to 20) Hz	0.024 % of reading + 4 μV	
	(20 to 40) Hz	0.009 % of reading + 4 μV	
	40 Hz to 20 kHz	0.008 % of reading + 4 μV	
	(20 to 50) kHz	0.02 % of reading + 4 μV	
	(50 to 100) kHz	0.05 % of reading + 5 μV	
	(100 to 300) kHz	0.11 % of reading + 10 μV	
	(300 to 500) kHz	0.14 % of reading + 20 μV	
	500 kHz to 1 MHz	0.27 % of reading + 20 μV	

Electrical – DC/Low Frequency

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
AC Voltage – Source ¹	(22 to 220) mV		Comparison to Fluke 5730A Multiproduct Calibrator
	(10 to 20) Hz	0.024 % of reading + 12 μ V	
	(20 to 40) Hz	0.009 % of reading + 7 μ V	
	40 Hz to 20 kHz	0.005 7 % of reading + 7 μ V	
	(20 o 50) kHz	0.012 % of reading + 7 μ V	
	(50 to 100) kHz	0.031 % of reading + 17 μ V	
	(100 to 300) kHz	0.066 % of reading + 20 μ V	
	(300 to 500) kHz	0.14 % of reading + 25 μ V	
	500 kHz to 1 MHz	0.27 % of reading + 45 μ V	
	(0.22 to 2.2) V		
	(10 to 20) Hz	0.024 % of reading + 40 μ V	
	(20 to 40) Hz	0.009 % of reading + 15 μ V	
	40 Hz to 20 kHz	0.004 2 % of reading + 8 μ V	
	(20 o 50) kHz	0.006 7 % of reading + 10 μ V	
	(50 to 100) kHz	0.008 5 % of reading + 30 μ V	
	(100 to 300) kHz	0.034 % of reading + 80 μ V	
	(300 to 500) kHz	0.1 % of reading + 0.2 mV	
	500 kHz to 1 MHz	0.17 % of reading + 0.3 mV	
	(2.2 to 22) V		
	(10 to 20) Hz	0.024 % of reading + 0.4 mV	
	(20 to 40) Hz	0.009 % of reading + 0.15 mV	
	40 Hz to 20 kHz	0.004 2 % of reading + 50 μ V	
	(20 o 50) kHz	0.006 7 % of reading + 0.1 mV	
	(50 to 100) kHz	0.008 3 % of reading + 0.2 mV	
	(100 to 300) kHz	0.26 % of reading + 0.6 mV	
	(300 to 500) kHz	0.1 % of reading + 2 mV	
	500 kHz to 1 MHz	0.15 % of reading + 3.2 mV	
	(22 to 220) V		
	(10 to 20) Hz	0.024 % of reading + 4 mV	
	(20 to 40) Hz	0.009 % of reading + 1.5 mV	
	40 Hz to 20 kHz	0.005 2 % of reading + 0.6 mV	
	(20 o 50) kHz	0.008 % of reading + 1 mV	
	(50 to 100) kHz	0.015 % of reading + 2.5 mV	
	(100 to 300) kHz	0.09 % of reading + 16 mV	
	(300 to 500) kHz	0.44 % of reading + 40 mV	
	500 kHz to 1 MHz	0.8 % of reading + 80 mV	
	(220 to 250) V		
	(15 to 50) Hz	0.03 % of reading + 16 mV	
	(250 to 1 100) V		
	50 Hz to 1 kHz	0.007 % of reading + 3.5 mV	

Electrical – DC/Low Frequency

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
AC Voltage – Source ¹	(220 to 750) V (30 to 50) kHz (50 to 100) kHz (220 to 1 100) V 40 Hz to 1 kHz (1 to 20) kHz	0.06 % of reading + 11 mV 0.23 % of reading + 45 mV 0.009 % of reading + 4 mV 0.017 % of reading + 6 mV	Comparison to Fluke 5730A Multiproduct Calibrator, Fluke 5725A Amplifier
AC Voltage – Source ¹ Wideband Flatness (into 50 Ω load) (1 kHz Reference)	(0.33 to 1.1) mV (10 to 30) Hz (30 to 119.99) Hz 120 Hz to 1.199 9 kHz (1.2 to 11.999) kHz (12 to 119.99) kHz 120 kHz to 1.199 9 MHz (1.2 to 2) MHz (2 to 11.9) MHz (12 to 20) MHz (20 to 30) MHz (1.1 to 3.3) mV (10 to 30) Hz (30 to 119.99) Hz 120 Hz to 1.199 9 kHz (1.2 to 11.999) kHz (12 to 119.99) kHz 120 kHz to 1.199 9 MHz (1.2 to 2) MHz (2 to 11.9) MHz (12 to 20) MHz (20 to 30) MHz (3.3 to 11) mV (10 to 30) Hz (30 to 119.99) Hz 120 Hz to 1.199 9 kHz (1.2 to 11.999) kHz (12 to 119.99) kHz 120 kHz to 1.199 9 MHz (1.2 to 2) MHz (2 to 11.9) MHz (12 to 20) MHz (20 to 30) MHz	0.23 % of reading 0.078 % of reading 0.078 % of reading 0.078 % of reading 0.078 % of reading 0.16 % of reading + 1.2 μ V 0.16 % of reading + 1.2 μ V 0.31 % of reading + 1.2 μ V 0.47 % of reading + 1.2 μ V 2.1 % of reading + 5.8 μ V 0.23 % of reading 0.078 % of reading 0.078 % of reading 0.078 % of reading 0.078 % of reading 0.078 % of reading + 1.2 μ V 0.078 % of reading + 1.2 μ V 0.23 % of reading + 1.2 μ V 0.39 % of reading + 1.2 μ V 1.2 % of reading + 1.2 μ V 0.23 % of reading 0.078 % of reading 0.078 % of reading 0.078 % of reading 0.078 % of reading 0.078 % of reading + 1.2 μ V 0.078 % of reading + 1.2 μ V 0.16 % of reading + 1.2 μ V 0.31 % of reading + 1.2 μ V 0.78 % of reading + 1.2 μ V	Comparison to Fluke 5730A/03 Multiproduct Calibrator

Electrical – DC/Low Frequency

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
AC Voltage – Source ¹ Wideband Flatness (into 50 Ω load) (1 kHz Reference)	(11 to 33) mV		Comparison to Fluke 5730A/03 Multiproduct Calibrator
	(10 to 30) Hz	0.23 % of reading	
	(30 to 119.99) Hz	0.078 % of reading	
	120 Hz to 1.199 9 kHz	0.078 % of reading	
	(1.2 to 11.999) kHz	0.078 % of reading	
	(12 to 119.99) kHz	0.078 % of reading	
	120 kHz to 1.199 9 MHz	0.078 % of reading + 1.2 μ V	
	(11 to 16.5) mV		
	(1.2 to 2) MHz	0.16 % of reading + 1.2 μ V	
	(2 to 11.9) MHz	0.23 % of reading + 1.2 μ V	
	(12 to 20) MHz	0.39 % of reading + 1.2 μ V	
	(20 to 30) MHz	0.85 % of reading + 1.2 μ V	
	(16.5 to 33) mV		
	(1.2 to 2) MHz	0.078 % of reading + 1.2 μ V	
	(2 to 11.9) MHz	0.16 % of reading + 1.2 μ V	
	(12 to 20) MHz	0.31 % of reading + 1.2 μ V	
	(20 to 30) MHz	0.78 % of reading + 1.2 μ V	
	(33 to 110) mV		
	(10 to 30) Hz	0.23 % of reading	
	(30 to 119.99) Hz	0.078 % of reading	
	120 Hz to 1.199 9 kHz	0.078 % of reading	
	(1.2 to 11.999) kHz	0.078 % of reading	
	(12 to 119.99) kHz	0.078 % of reading	
	120 kHz to 1.199 9 MHz	0.078 % of reading + 1.2 μ V	
	(110 to 330) mV		
	(10 to 30) Hz	0.23 % of reading	
	(30 to 119.99) Hz	0.078 % of reading	
	120 Hz to 1.199 9 kHz	0.078 % of reading	
	(1.2 to 11.999) kHz	0.078 % of reading	
	(12 to 119.99) kHz	0.078 % of reading	
	120 kHz to 1.199 9 MHz	0.078 % of reading + 1.2 μ V	

Electrical – DC/Low Frequency

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
AC Voltage – Source ¹ Wideband Flatness (into 50 Ω load) (1 kHz Reference)	(0.33 to 1.1) V		Comparison to Fluke 5730A/03 Multiproduct Calibrator
	(10 to 30) Hz	0.23 % of reading	
	(30 to 119.99) Hz	0.078 % of reading	
	120 Hz to 1.199 9 kHz	0.078 % of reading	
	(1.2 to 11.999) kHz	0.078 % of reading	
	(12 to 119.99) kHz	0.078 % of reading	
	120 Hz to 1.199 9 MHz	0.078 % of reading + 1.2 μ V	
	(1.1 to 3.5) V		
	(10 to 30) Hz	0.23 % of reading	
	(30 to 119.99) Hz	0.078 % of reading	
AC Voltage – Measure ¹	120 Hz to 1.199 9 kHz	0.078 % of reading	Comparison to Agilent 3458A opt 002 8.5 Digit Multimeter
	(1.2 to 11.999) kHz	0.078 % of reading	
	(12 to 119.99) kHz	0.078 % of reading	
	120 kHz to 1.199 9 MHz	0.078 % of reading + 1.2 μ V	
	Up to 10 mV		
	(1 to 40) Hz	0.04 % of reading + 3.5 μ V	
	40 Hz to 1 kHz	0.03 % of reading + 1.3 μ V	
	(1 to 20) kHz	0.04 % of reading + 1.3 μ V	
	(20 to 50) kHz	0.15 % of reading + 1.3 μ V	
	(50 to 100) kHz	0.59 % of reading + 1.3 μ V	
	(100 to 300) kHz	4.6 % of reading + 2.3 μ V	
	300 kHz to 1 MHz	1.5 % of reading + 5.8 μ V	
	(1 to 4) MHz	8.1 % of reading + 8.1 μ V	
	(10 to 100) mV		
	(1 to 40) Hz	0.013 % of reading + 4.6 μ V	
	40 Hz to 1 kHz	0.009 7 % of reading + 2.3 μ V	
	(1 to 20) kHz	0.017 % of reading + 2.3 μ V	
	(20 to 50) kHz	0.038 % of reading + 2.3 μ V	
	(50 to 100) kHz	0.093 % of reading + 2.3 μ V	
	(100 to 300) kHz	0.36 % of reading + 12 μ V	
	300 kHz to 1 MHz	1.2 % of reading + 12 μ V	
	(1 to 2) MHz	1.8 % of reading + 12 μ V	
	(2 to 4) MHz	4.7 % of reading + 81 μ V	
	(4 to 8) MHz	4.7 % of reading + 92 μ V	
	(8 to 10) MHz	17 % of reading + 0.1 mV	

Electrical – DC/Low Frequency

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
AC Voltage – Measure ¹	(0.1 to 1) V		Comparison to Agilent 3458A opt 002 8.5 Digit Multimeter
	(1 to 40) Hz	0.008 8 % of reading + 46 μ V	
	40 Hz to 1 kHz	0.008 3 % of reading + 23 μ V	
	(1 to 20) kHz	0.017 % of reading + 23 μ V	
	(20 to 50) kHz	0.036 % of reading + 23 μ V	
	(50 to 100) kHz	0.093 % of reading + 23 μ V	
	(100 to 300) kHz	0.35 % of reading + 0.12 mV	
	300 kHz to 1 MHz	1.2 % of reading + 0.12 mV	
	(1 to 2) MHz	1.8 % of reading + 0.12 mV	
	(2 to 4) MHz	4.6 % of reading + 0.81 mV	
	(4 to 8) MHz	4.6 % of reading + 0.92 mV	
	(8 to 10) MHz	17 % of reading + 1.2 mV	
	(1 to 10) V		
	(1 to 40) Hz	0.009 5 % of reading + 0.46 mV	
	40 Hz to 1 kHz	0.023 % of reading + 0.23 mV	
	(1 to 20) kHz	0.017 % of reading + 0.23 mV	
	(20 to 50) kHz	0.036 % of reading + 0.23 mV	
	(50 to 100) kHz	0.093 % of reading + 0.23 mV	
	(100 to 300) kHz	0.35 % of reading + 1.2 mV	
	300 kHz to 1 MHz	1.2 % of reading + 1.2 mV	
	(1 to 2) MHz	1.8 % of reading + 1.2 mV	
	(2 to 4) MHz	4.6 % of reading + 8.1 mV	
	(4 to 8) MHz	4.6 % of reading + 9.2 mV	
	(8 to 10) MHz	17 % of reading + 12 mV	
	(10 to 100) V		
	(1 to 40) Hz	0.024 % of reading + 4.6 mV	
	40 Hz to 1 kHz	0.024 % of reading + 2.3 mV	
	(1 to 20) kHz	0.024 % of reading + 2.3 mV	
	(20 to 50) kHz	0.041 % of reading + 2.3 mV	
	(50 to 100) kHz	0.14 % of reading + 2.3 mV	
	(100 to 300) kHz	0.46 % of reading + 12 mV	
	300 kHz to 1 MHz	1.7 % of reading + 12 mV	
	(100 to 700) V		
	(1 to 40) Hz	0.048 % of reading + 46 mV	
	40 Hz to 1 kHz	0.048 % of reading + 23 mV	
	(1 to 20) kHz	0.071 % of reading + 23 mV	
	(20 to 50) kHz	0.19 % of reading + 23 mV	
	(50 to 100) kHz	0.35 % of reading + 23 mV	

Electrical – DC/Low Frequency

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
AC Voltage – Measure ¹	Up to 1 mV 100 kHz to 1 MHz (1 to 3) MHz (3 to 10) MHz (10 to 20) MHz	2 % of reading + 2.4 μ V 3.5 % of reading + 2.4 μ V 9.3 % of reading + 2.4 μ V 23 % of reading + 2.4 μ V	Comparison to Rohde & Schwarz URE3 RMS Voltmeter
	(1 to 3) mV 100 kHz to 1 MHz (1 to 3) MHz (3 to 10) MHz (10 to 20) MHz	0.97 % of reading + 2 μ V 3.5 % of reading + 2 μ V 9.3 % of reading + 2 μ V 23 % of reading + 2 μ V	
	(3 to 100) mV 100 kHz to 1 MHz (1 to 3) MHz (3 to 10) MHz (10 to 20) MHz (20 to 30) MHz	0.91 % of reading + 3 μ V 1.8 % of reading + 3 μ V 2.9 % of reading + 3 μ V 6.9 % of reading + 3 μ V 14 % of reading + 3 μ V	
AC High Voltage – Measure ¹	(0.7 to 5) kV 10 mHz to 10 Hz (10 to 30) Hz (30 to 200) Hz (200 to 450) Hz (450 to 600) Hz	0.15 % of reading + 0.17 V 0.13 % of reading + 0.29 V 0.11 % of reading + 0.37 V 0.48 % of reading + 0.17 V 0.88 % of reading + 0.17 V	Comparison to Vitretek 4700 Digital HV Meter, Vitretek HVL Series Probes
	(5 to 30) kV 10 mHz to 10 Hz (10 to 30) Hz (30 to 200) Hz (200 to 450) Hz (450 to 600) Hz	0.2 % of reading + 2.4 V 0.15 % of reading + 2.4 V 0.12 % of reading + 2.4 V 0.71 % of reading + 2.4 V 1.4 % of reading + 2.4 V	
	(30 to 50) kV 10 mHz to 10 Hz (10 to 30) Hz (30 to 70) Hz (70 to 200) Hz (200 to 450) Hz	0.25 % of reading + 2.5 V 0.19 % of reading + 2.5 V 0.14 % of reading + 2.5 V 0.7 % of reading + 2.5 V 2.9 % of reading + 2.5 V	
	(50 to 70) kV 10 mHz to 10 Hz (10 to 30) Hz (30 to 70) Hz (70 to 200) Hz (200 to 450) Hz	0.37 % of reading + 2.6 V 0.27 % of reading + 2.6 V 0.18 % of reading + 2.6 V 1.2 % of reading + 2.6 V 1.7 % of reading + 2.6 V	

Electrical – DC/Low Frequency

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
DC Voltage – Source ¹	(0 to 220) mV (0.22 to 2.2) V (2.2 to 11) V (11 to 22) V (22 to 220) V (220 to 1 100) V	7.5 $\mu\text{V/V}$ + 0.4 μV 5 $\mu\text{V/V}$ + 0.7 μV 3.5 $\mu\text{V/V}$ + 2.5 μV 3.5 $\mu\text{V/V}$ + 4 μV 5 $\mu\text{V/V}$ + 40 μV 6.5 $\mu\text{V/V}$ + 0.4 mV	Comparison to Fluke 5730A Multiproduct Calibrator
DC Voltage – Measure ¹	Up to 100 mV (0.1 to 10) V (10 to 100) V (100 to 500) V (500 to 700) V (700 to 1 000) V	8.3 $\mu\text{V/V}$ + 0.35 μV 5.3 $\mu\text{V/V}$ + 0.35 μV 7.6 $\mu\text{V/V}$ + 35 μV 11 $\mu\text{V/V}$ + 0.12 mV 14 $\mu\text{V/V}$ + 0.12 mV 21 $\mu\text{V/V}$ + 0.12 mV	Comparison to Agilent 3458A opt 002 8.5 Digit Multimeter
DC High Voltage – Measure ¹	(1 to 10) kV (10 to 35) kV (35 to 50) kV (50 to 70) kV (70 to 100) kV	0.042 % of reading + 92 mV 0.047 % of reading + 2.4 V 0.056 % of reading + 2.4 V 0.088 % of reading + 2.4 V 0.17 % of reading + 2.5 V	Comparison to Vitretek 4700 Digital HV Meter, Vitretek HVL Series Probes
Capacitance – Source ¹ (Simulation)	10 Hz to 10 kHz (0.19 to < 1.1) nF 10 Hz to 3 kHz (1.1 to < 3.3) nF 10 Hz to 1 kHz (3.3 to < 11) nF (11 to < 110) nF (110 to < 330) nF (10 to 600) Hz (0.33 to < 1.1) μF (10 to 300) Hz (1.1 to < 3.3) μF (10 to 150) Hz (3.3 to < 11) μF (10 to 120) Hz (11 to < 33) μF (10 to 80) Hz (33 to < 110) μF DC to 50 Hz (110 to < 330) μF	0.39 % of reading + 7.8 pF 0.39 % of reading + 7.8 pF 0.21 % of reading + 7.8 pF 0.21 % of reading + 78 pF 0.21 % of reading + 0.23 nF 0.21 % of reading + 0.78 nF 0.21 % of reading + 2.3 nF 0.21 % of reading + 7.8 nF 0.32 % of reading + 23 nF 0.36 % of reading + 78 nF 0.36 % of reading + 0.23 μF	Comparison to Fluke 5520A Multiproduct Calibrator

Electrical – DC/Low Frequency

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
Capacitance – Source ¹ (Simulation)	DC to 20 Hz (0.33 to < 1.1) mF	0.35 % of reading + 0.78 μ F	Comparison to Fluke 5520A Multiproduct Calibrator
	DC to 6 Hz (1.1 to < 3.3) mF	0.35 % of reading + 2.3 μ F	
	DC to 2 Hz (3.3 to < 11) mF	0.35 % of reading + 7.8 μ F	
	DC to 0.6 Hz (11 to < 33) mF	0.58 % of reading + 23 μ F	
	DC to 0.2 Hz (33 to < 110) mF	0.85 % of reading + 78 μ F	
Electrical Simulation of Thermocouple Indicating Devices – Measure/Source ¹	Type B (250 to 350) °C	1.2 °C	Comparison to Ectron 1140A Thermocouple Calibrator/Simulator
	(350 to 445) °C	0.9 °C	
	(445 to 580) °C	0.71 °C	
	(580 to 750) °C	0.55 °C	
	(750 to 1 000) °C	0.45 °C	
	(1 000 to 1 820) °C	0.35 °C	
	Type C (0 to 250) °C	0.24 °C	
	(250 to 1 000) °C	0.19 °C	
	(1 000 to 1 500) °C	0.21 °C	
	(1 500 to 1 800) °C	0.24 °C	
	(1 800 to 2 000) °C	0.27 °C	
	(2 000 to 2 250) °C	0.33 °C	
	(2 250 to 2 315) °C	0.37 °C	
	Type E (-270 to -245) °C	1.6 °C	
	(-245 to -195) °C	0.24 °C	
	(-195 to -155) °C	0.12 °C	
	(-155 to -90) °C	0.095 °C	
	(-90 to 0) °C	0.08 °C	
	(0 to 15) °C	0.076 °C	
	(15 to 890) °C	0.064 °C	
	(890 to 1 000) °C	0.074 °C	
	Type J (-210 to -180) °C	0.15 °C	
	(-180 to -120) °C	0.12 °C	
	(-120 to -50) °C	0.093 °C	
	(-50 to 990) °C	0.08 °C	
	(990 to 1 200) °C	0.094 °C	

Electrical – DC/Low Frequency

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
Electrical Simulation of Thermocouple Indicating Devices – Measure/Source ¹	Type K		Comparison to Ectron 1140A Thermocouple Calibrator/Simulator
	(-270 to -255) °C	2.5 °C	
	(-255 to -195) °C	0.85 °C	
	(-195 to -115) °C	0.16 °C	
	(-115 to -55) °C	0.12 °C	
	(-55 to 1 000) °C	0.087 °C	
	(1 000 to 1 372) °C	0.096 °C	
	Type N		
	(-270 to -260) °C	5.4 °C	
	(-260 to -200) °C	1.5 °C	
	(-200 to -140) °C	0.29 °C	
	(-140 to -70) °C	0.18 °C	
	(-70 to 25) °C	0.14 °C	
	(-25 to 160) °C	0.12 °C	
	(160 to 1 300) °C	0.11 °C	
	Type R		
	(-50 to -30) °C	0.8 °C	
	(-30 to 45) °C	0.69 °C	
	(45 to 160) °C	0.49 °C	
	(160 to 380) °C	0.35 °C	
	(380 to 775) °C	0.3 °C	
	(775 to 1 768) °C	0.26 °C	
	Type S		
	(-50 to -30) °C	0.76 °C	
	(-30 to 45) °C	0.68 °C	
	(45 to 105) °C	0.49 °C	
	(105 to 310) °C	0.41 °C	
	(310 to 615) °C	0.35 °C	
	(615 to 1 768) °C	0.31 °C	
	Type T		
	(-270 to -255) °C	1.9 °C	
	(-255 to -240) °C	0.6 °C	
	(-240 to -210) °C	0.36 °C	
	(-210 to -150) °C	0.22 °C	
	(-150 to -40) °C	0.15 °C	
	(-40 to 100) °C	0.095 °C	
	(100 to 400) °C	0.08 °C	

Electrical – DC/Low Frequency

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
Electrical Simulation of Thermocouple Indicating Devices – Source ¹	Type L (-200 to -100) °C (-100 to 800) °C (800 to 900) °C Type U (-200 to 0) °C (0 to 600) °C	0.37 °C 0.26 °C 0.17 °C 0.56 °C 0.27 °C	Comparison to Fluke 5520A Multiproduct Calibrator
Resistance Simulation of RTD Indicators – Source ¹	Pt 385, 100 Ω (-200 to -80) °C (-80 to 0) °C (0 to 100) °C (100 to 300) °C (300 to 400) °C (400 to 630) °C (630 to 800) °C Pt 3926, 100 Ω (-200 to -80) °C (-80 to 0) °C (0 to 100) °C (100 to 300) °C (300 to 400) °C (400 to 630) °C Pt 3916, 100 Ω (-200 to -190) °C (-190 to -80) °C (-80 to 0) °C (0 to 100) °C (100 to 260) °C (260 to 300) °C (300 to 400) °C (400 to 600) °C (600 to 630) °C Pt 385, 200 Ω (-200 to -80) °C (-80 to 0) °C (0 to 100) °C (100 to 260) °C (260 to 300) °C (300 to 400) °C (400 to 600) °C (600 to 630) °C	0.05 °C 0.05 °C 0.07 °C 0.09 °C 0.1 °C 0.12 °C 0.23 °C 0.05 °C 0.05 °C 0.07 °C 0.09 °C 0.1 °C 0.12 °C 0.25 °C 0.04 °C 0.05 °C 0.06 °C 0.07 °C 0.08 °C 0.09 °C 0.1 °C 0.23 °C 0.04 °C 0.04 °C 0.04 °C 0.05 °C 0.12 °C 0.13 °C 0.14 °C 0.16 °C	Comparison to Fluke 5520A Multiproduct Calibrator

This Scope of Accreditation, version 015, was last updated on: 25 June 2026 and is valid only when accompanied by the Certificate.

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Electrical – DC/Low Frequency

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
Resistance Simulation of RTD Indicators – Source ¹	Pt 385, 500 Ω		Comparison to Fluke 5520A Multiproduct Calibrator
	(-200 to -80) °C	0.04 °C	
	(-80 to 0) °C	0.05 °C	
	(0 to 100) °C	0.05 °C	
	(100 to 260) °C	0.06 °C	
	(260 to 300) °C	0.08 °C	
	(300 to 400) °C	0.08 °C	
	(400 to 600) °C	0.09 °C	
	(600 to 630) °C	0.11 °C	
	Pt 385, 1 000 Ω		
	(-200 to -80) °C	0.03 °C	
	(-80 to 0) °C	0.03 °C	
	(0 to 100) °C	0.04 °C	
	(100 to 260) °C	0.05 °C	
	(260 to 300) °C	0.06 °C	
	(300 to 400) °C	0.07 °C	
	(400 to 600) °C	0.07 °C	
	(600 to 630) °C	0.23 °C	
	PtNi 385, 120 Ω (Ni 120)		
	(-80 to 0) °C	0.08 °C	
	(0 to 100) °C	0.08 °C	
	(100 to 260) °C	0.14 °C	
	Cu 427, 10 Ω		
	(100 to 260) °C	0.3 °C	
DC Power – Source ¹ (0.33 to 330) mA	11 μ W to 1.1 mW 1.1 mW to 0.11 W (0.11 to 110) W (110 to 330) W	0.024 % of reading 0.027 % of reading 0.024 % of reading 0.018 % of reading	Comparison to Fluke 5520A Multiproduct Calibrator
(0.33 to 3) A	11 μ W to 110 mW (0.11 to 990) W (0.99 to 3) kW	0.044 % of reading 0.053 % of reading 0.009 6 % of reading	
(3 to 20.5) A	99 mW to 0.99 W 0.99 W to 6.8 kW (6.8 to 20.5) kW	0.088 % of reading 0.07 % of reading 0.04 % of reading	

Electrical – DC/Low Frequency

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
AC Power – Source ^{1,2} PF = 1 (3.3 to 9) mA	(10 to 65) Hz (0.11 mW to 3) mW 3 mW to 9 W	0.13 % of reading 0.077 % of reading	Comparison to Fluke 5520A Multiproduct Calibrator
(9 to 33) mA	(10 to 65) W (0.3 to 10) mW 10 mW to 33 W	0.089 % of reading 0.077 % of reading	
AC Power – Source ^{1,2} PF = 1 (33 to 90) mA	(10 to 65) Hz (1 to 30) mW 30 mW to 90 W	0.071 % of reading 0.057 % of reading	Comparison to Fluke 5520A Multiproduct Calibrator
(90 to 330) mA	(10 to 65) Hz (3 to 100) mW 100 mW to 300 W	0.089 % of reading 0.078 % of reading	
(0.33 to 0.9) A	(10 to 65) Hz (11 to 300) mW (0.3 to 900) W	0.071 % of reading 0.081 % of reading	
(0.9 to 2.2) A	(10 to 65) Hz (30 to 720) mW 0.72 W to 2 kW	0.089 % of reading 0.079 % of reading	
(2.2 to 4.5) A	(10 to 65) Hz 80 mW to 1.4 W 1.4 W to 4.5 kW	0.088 % of reading 0.18 % of reading	
(4.5 to 20.5) A	(10 to 65) Hz 150 mW to 230 kW	0.17 % of reading	
LF Phase – Source ¹	(0 to 90)° (10 to 65) Hz (65 to 500) Hz 500 Hz to 1 kHz (1 to 5) kHz (5 to 10) kHz (10 to 30) kHz	0.11° 0.2° 0.39° 1.9° 3.9° 7.8°	Comparison to Fluke 5520A Multiproduct Calibrator

Electrical – DC/Low Frequency

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
Oscilloscopes ¹			
Amplitude DC – Source			
into 50 Ω load	(-6 to 6) V	0.22 % of reading + 31 μ V	
into 1 M Ω load	(-130 to 130) V	0.12 % of reading + 31 μ V	
Square Wave – Source			
into 50 Ω load	10 Hz to 100 kHz 1 mV p-p to 6.6 Vp-p	0.22 % of reading + 31 μ V	
into 1 M Ω load	10 Hz to 1 kHz 1 mV p-p to 6.6 Vp-p (1 kHz to 10) kHz 1 mV p-p to 6.6 Vp-p	0.14 % of reading + 31 μ V 0.22 % of reading + 31 μ V	
Time Markers – Source			
into 50 Ω load	1 ns to 20 ms 50 ms 0.1 s 0.2 s 0.5 s 1 s 2 s 5 s	0.000 22 % of reading 0.005 9 % of reading 0.009 8 % of reading 0.018 % of reading 0.041 % of reading 0.08 % of reading 0.16 % of reading 0.39 % of reading	
Rise Time – Source ¹			
into 50 Ω load			
Rate: 1 kHz to 2 MHz	5 mVp-p to 2.5 Vp-p (200 to 300) ps	50 ps	
Rate: 2 MHz to 10 MHz	(250 to 350) ps	50 ps	
			Comparison to Fluke 5520A/SC1100 Multiproduct Calibrator

Electrical – DC/Low Frequency

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
Oscilloscopes ^{1,3} Leveled Sine Wave – Source into 50 Ω load	5 mVp-p to 5 Vp-p 50 kHz 50 kHz to 100 MHz (100 to 300) MHz (300 to 600) MHz 5 mVp-p to 3.5 Vp-p 600 MHz to 1.1 GHz	1.8 % of reading + 0.23 mV 2.8 % of reading + 0.23 mV 3.2 % of reading + 0.23 mV 4 % of reading + 0.23 mV 5 % of reading + 0.23 mV	Comparison to Fluke 5520A/SC1100 Multiproduct Calibrator
Bandwidth/Flatness – Source (50 kHz Reference) into 50 Ω load	5 mVp-p to 5.5 Vp-p 50 kHz to 100 MHz (100 to 300) MHz (300 to 600) MHz 5 mVp-p to 3.5 Vp-p 600 MHz to 1.1 GHz	1.4 % of reading + 78 μ V 1.8 % of reading + 78 μ V 3.2 % of reading + 78 μ V 3.9 % of reading + 78 μ V	
Input Impedance – Measure	(40 to 60) Ω (0.5 to 1.5) M Ω	0.082 % of reading 0.081 % of reading	
Input Capacitance – Measure	(5 to 50) pF	3.9 % of reading + 0.39 pF	
Waveform Generator – Source Amplitude (Sine, Square, Triangle) into 50 Ω load into 1 M Ω load	10 Hz to 10 kHz 1.8 mVp-p to 2.5 Vp-p 1.8 mVp-p to 55 Vp-p	2.3 % of reading + 78 μ V 2.3 % of reading + 78 μ V	
Frequency (Sine, Square, Triangle)	10 Hz to 10 kHz	0.001 9 % of reading + 12 mHz	

Electrical – RF/Microwave

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
Total Harmonic Distortion	20 Hz to 100 kHz	0.7 dB	Comparison to HP 8903B Audio Analyzer
Total Harmonic Distortion	100 kHz to 2.9 GHz	1 dB	Comparison to HP 8563E Spectrum Analyzer
Distortion – Measure	20 Hz to 20 kHz (20 to 100) kHz	1.2 dB 2.3 dB	Comparison to HP 8903B Audio Analyzer
RF Power – Power Meter Reference	50 MHz 1 mW Reference	0.43 % of reading	Comparison to Thermistor Mount, Analog Power Meter, 8.5 Digit Multimeter
RF Power – Measure	9 kHz to 10 MHz (-60 to < -50) dBm (-50 to < -40) dBm (-40 to < -20) dBm (-20 to < 10) dBm (10 to 20) dBm (20 to 30) dBm 10 MHz to 6 GHz (-70 to < -60) dBm (-60 to < -50) dBm (-50 to < -20) dBm (-20 to < 10) dBm (10 to 20) dBm (20 to 30) dBm (6 to 18) GHz (-70 to < -60) dBm (-60 to < -50) dBm (-50 to < -20) dBm (-20 to < 10) dBm (10 to 20) dBm (20 to 30) dBm (18 to 26.5) GHz (-30 to < -20) dBm (-20 to < 10) dBm (10 to 20) dBm (20 to 30) dBm	3.3 dB 0.29 dB 0.16 dB 0.1 dB 0.13 dB 0.23 dB 1.1 dB 0.16 dB 0.13 dB 0.11 dB 0.13 dB 0.27 dB 1.1 dB 0.16 dB 0.13 dB 0.11 dB 0.17 dB 0.27 dB 0.3 dB 0.18 dB 0.22 dB 0.27 dB	Comparison to Power Sensor, Power Meter, Sensor Module, Measuring Receiver

Electrical – RF/Microwave

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
Amplitude Modulation – Measure Rate: 50 Hz to 10 kHz Rate: 20 Hz to 10 kHz Rate: 50 Hz to 50 kHz	(5 to 99) % Depth 150 kHz to 10 MHz (> 0 to 99) % Depth 150 kHz to 10 MHz (5 to 99) % Depth 10 MHz to 1.3 GHz	2.4 % Depth 3.5 % Depth 1.4 % Depth	Comparison to HP 8902A Measuring Receiver
Amplitude Modulation – Measure Rate: 20 Hz to 100 kHz Rate: 50 Hz to 50 kHz Rate: 20 Hz to 100 kHz	(> 0 to 99) % Depth 10 MHz to 1.3 GHz (5 to 99) % Depth (1.3 to 26.5) GHz (> 0 to 99) % Depth (1.3 to 26.5) GHz	3.5 % Depth 1.9 % Depth 3.5 % Depth	Comparison to HP 8902A Measuring Receiver
Frequency Modulation – Measure Rate 50 Hz to 10 kHz Rate: 50 Hz to 100 kHz Rate: 20 Hz to 200 kHz	≤ 40 kHz peak 250 kHz to 10 MHz ≤ 400 kHz peak 10 MHz to 26.5 GHz ≤ 400 kHz peak 10 MHz to 26.5 GHz	2.4 % Deviation 1.4 % Deviation 5.8 % Deviation	Comparison to HP 8902A Measuring Receiver
Phase Modulation – Measure Rate: 200 Hz to 10 kHz Rate: 200 Hz to 20 kHz	< 40 rad Deviation 150 kHz to 10 MHz < 40 rad Deviation 10 MHz to 26.5 GHz	4.9 % Deviation 3.8 % Deviation	Comparison to HP 8902A Measuring Receiver

Electrical – RF/Microwave

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
Tuned RF Absolute Power – Measure	2.5 MHz to 26.5 GHz		Comparison to HP 8902A OPT 050 Measuring Receiver, HP 11722A Power Sensor; or HP 11792A, HP 11793A Power Sensors
	(-127 to -120) dBm	0.26 dB	
	(-120 to -110) dBm	0.26 dB	
	(-110 to -100) dBm	0.26 dB	
	(-100 to -90) dBm	0.26 dB	
	(-90 to -80) dBm	0.26 dB	
	(-80 to -70) dBm	0.25 dB	
	(-70 to -60) dBm	0.25 dB	
	(-60 to -50) dBm	0.25 dB	
	(-50 to -40) dBm	0.25 dB	
	(-40 to -30) dBm	0.14 dB	
	(-30 to -20) dBm	0.14 dB	
	(-20 to -10) dBm	0.14 dB	
	(-10 to 0) dBm	0.14 dB	
Tuned RF Relative Power – Measure	2.5 MHz to 26.5 GHz		Comparison to HP 8902A OPT 050 Measuring Receiver, HP 11722A Power Sensor; or HP 11792A, HP 11793A Power Sensors
	(-127 to -120) dBm	0.23 dB	
	(-120 to -110) dBm	0.23 dB	
	(-110 to -100) dBm	0.23 dB	
	(-100 to -90) dBm	0.23 dB	
	(-90 to -80) dBm	0.22 dB	
	(-80 to -70) dBm	0.084 dB	
	(-70 to -60) dBm	0.081 dB	
	(-60 to -50) dBm	0.074 dB	
	(-50 to -40) dBm	0.071 dB	
	(-40 to -30) dBm	0.068 dB	
	(-30 to -20) dBm	0.064 dB	
	(-20 to -10) dBm	0.06 dB	
	(-10 to 0) dBm	0.056 dB	

Electrical – RF/Microwave

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
Amplitude Modulation – Measure Rate 50 Hz to 10 kHz Rate: 50 Hz to 100 kHz Rate: 50 Hz to 100 kHz Rate: 20 Hz to 100 kHz Rate: 50 Hz to 100 kHz Rate 20 Hz to 1 kHz Rate 20 Hz to 1 kHz	(5 to 99) % Depth 10 kHz to 10 MHz (20 to 99) % Depth 10 MHz to 3 GHz (5 to 20) % Depth 10 MHz to 3 GHz (20 to 99) % Depth (3 to 26.5) GHz (5 to 20) % Depth (3 to 26.5) GHz > 1 % Depth 100 kHz to 10 MHz > 1 % Depth 10 MHz to 26.5 GHz	1 % Depth 0.9 % Depth 3 % Depth 1.9 % Depth 5.2 % Depth 15 % of reading 16 % of reading	Comparison to Agilent E4440A PSA Spectrum Analyzer
Frequency Modulation – Measure Rate 20 Hz to 10 kHz Rate 20 Hz to 10 kHz Rate 50 Hz to 200 kHz Rate 50 Hz to 200 kHz Rate 50 Hz to 200 kHz	Deviation/Rate > 0.2 250 kHz to 10 MHz Deviation/Rate > 1.2 250 kHz to 10 MHz Deviation/Rate > 0.2 10 MHz to 6.6 GHz Deviation/Rate > 0.45 10 MHz to 6.6 GHz Deviation/Rate > 0.2 (6.6 to 13.2) GHz	1.8 % Deviation 1.3 % Deviation 1.8 % Deviation 1.3 % Deviation 3 % Deviation	Comparison to Agilent E4440A PSA Spectrum Analyzer
Frequency Modulation – Measure Rate 50 Hz to 200 kHz Rate 50 Hz to 200 kHz Rate 50 Hz to 200 kHz	Deviation/Rate > 8 (6.6 to 13.2) GHz Deviation/Rate > 0.2 (13.2 to 26.5) GHz Deviation/Rate > 16 (13.2 to 26.5) G	1.3 % Deviation 4.8 % Deviation 1.3 % Deviation	Comparison to Agilent E4440A PSA Spectrum Analyzer

Electrical – RF/Microwave

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
Frequency Modulation Distortion – Measure			
Rate 20 Hz to 1 kHz	Deviation > 500 Hz	14 % of reading	Comparison to Agilent E4440A PSA Spectrum Analyzer
Rate 20 Hz to 1 kHz	1 MHz to 6.6 GHz	14 % of reading	
Rate 20 Hz to 1 kHz	Deviation > 2.3 kHz (6.6 to 13.2) GHz	14 % of reading	
Rate 20 Hz to 1 kHz	Deviation > 2.7 kHz (13.2 to 26.5) GHz	14 % of reading	
Phase Modulation – Measure			
	> 0.7 rad	1.3 % of reading	Comparison to Agilent E4440A PSA Spectrum Analyzer
	100 kHz to 6.6 GHz	3.5 % of reading	
	> 0.3 rad	1.3 % of reading	
	100 kHz to 6.6 GHz	3.5 % of reading	
	> 2 rad	1.3 % of reading	
	(6.6 to 13.2) GHz	3.5 % of reading	
	> 0.6 rad	1.3 % of reading	
	(6.6 to 13.2) GHz	3.5 % of reading	
	> 4 rad	1.3 % of reading	
	(13.2 to 26.5) GHz	3.5 % of reading	
	> 1.2 rad	3.5 % of reading	
	(13.2 to 26.5) GHz		
Phase Modulation Distortion – Measure			
Rate 20 Hz to 500 Hz	> 0.8 rad	16 % of reading	Comparison to Agilent E4440A PSA Spectrum Analyzer
	1 MHz to 6.6 GHz	15 % of reading	
Rate 500 Hz to 1 kHz	> 0.4 rad	17 % of reading	
	1 MHz to 6.6 GHz	14 % of reading	
Rate 20 Hz to 500 Hz	> 1.8 rad	15 % of reading	
	(6.6 to 13.2) GHz	14 % of reading	
Rate 500 Hz to 1 kHz	> 0.8 rad	15 % of reading	
	(6.6 to 13.2) GHz	14 % of reading	
Rate 20 Hz to 500 Hz	> 3.5 rad	15 % of reading	
	(13.2 to 26.5) GHz	14 % of reading	
Rate 500 Hz to 1 kHz	> 1.2 rad	14 % of reading	
	(13.2 to 26.5) GHz		

Electrical – RF/Microwave

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
Tuned RF Relative Power – Measure	100 kHz to 2 MHz		Comparison to Agilent E4440A PSA Spectrum Analyzer
	(-127 to -120) dB	1.1 dB	
	(-120 to -110) dB	0.61 dB	
	(-110 to -100) dB	0.19 dB	
	(-100 to -90) dB	0.092 dB	
	(-90 to -80) dB	0.08 dB	
	(-80 to -70) dB	0.076 dB	
	(-70 to -60) dB	0.058 dB	
	(-60 to -50) dB	0.052 dB	
	(-50 to -40) dB	0.051 dB	
	(-40 to -30) dB	0.042 dB	
	(-30 to -20) dB	0.036 dB	
	(-20 to -10) dB	0.03 dB	
	(-10 to 0) dB	0.024 dB	
	(2 to 10) MHz		
	(-127 to -120) dB	0.73 dB	
	(-120 to -110) dB	0.37 dB	
	(-110 to -100) dB	0.11 dB	
	(-100 to -90) dB	0.085 dB	
	(-90 to -80) dB	0.08 dB	
	(-80 to -70) dB	0.068 dB	
	(-70 to -60) dB	0.06 dB	
	(-60 to -50) dB	0.055 dB	
	(-50 to -40) dB	0.054 dB	
	(-40 to -30) dB	0.045 dB	
	(-30 to -20) dB	0.039 dB	
	(-20 to -10) dB	0.034 dB	
	(-10 to 0) dB	0.029 dB	

Electrical – RF/Microwave

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
Tuned RF Relative Power – Measure	10 MHz to 6.6 GHz		Comparison to Agilent E4440A PSA Spectrum Analyzer
	(-127 to -120) dB	0.41 dB	
	(-120 to -110) dB	0.17 dB	
	(-110 to -100) dB	0.1 dB	
	(-100 to -90) dB	0.085 dB	
	(-90 to -80) dB	0.072 dB	
	(-80 to -70) dB	0.068 dB	
	(-70 to -60) dB	0.06 dB	
	(-60 to -50) dB	0.055 dB	
	(-50 to -40) dB	0.054 dB	
	(-40 to -30) dB	0.045 dB	
	(-30 to -20) dB	0.039 dB	
	(-20 to -10) dB	0.034 dB	
	(-10 to 0) dB	0.029 dB	
	(6.6 to 13.2) GHz		
	(-127 to -120) dB	0.67 dB	
	(-120 to -110) dB	0.33 dB	
	(-110 to -100) dB	0.11 dB	
	(-100 to -90) dB	0.085 dB	
	(-90 to -80) dB	0.08 dB	
	(-80 to -70) dB	0.068 dB	
	(-70 to -60) dB	0.06 dB	
	(-60 to -50) dB	0.055 dB	
	(-50 to -40) dB	0.054 dB	
	(-40 to -30) dB	0.045 dB	
	(-30 to -20) dB	0.039 dB	
	(-20 to -10) dB	0.034 dB	
	(-10 to 0) dB	0.029 dB	

Electrical – RF/Microwave

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
Tuned RF Relative Power – Measure	(13.2 to 18) GHz		Comparison to Agilent E4440A PSA Spectrum Analyzer
	(-127 to -120) dB	1.1 dB	
	(-120 to -110) dB	0.61 dB	
	(-110 to -100) dB	0.19 dB	
	(-100 to -90) dB	0.092 dB	
	(-90 to -80) dB	0.08 dB	
	(-80 to -70) dB	0.076 dB	
	(-70 to -60) dB	0.06 dB	
	(-60 to -50) dB	0.055 dB	
	(-50 to -40) dB	0.054 dB	
	(-40 to -30) dB	0.045 dB	
	(-30 to -20) dB	0.039 dB	
	(-20 to -10) dB	0.034 dB	
	(-10 to 0) dB	0.029 dB	
	(18 to 26.5) GHz		
	(-127 to -120) dB	1.8 dB	
	(-120 to -110) dB	1.2 dB	
	(-110 to -100) dB	0.51 dB	
	(-100 to -90) dB	0.14 dB	
	(-90 to -80) dB	0.08 dB	
	(-80 to -70) dB	0.076 dB	
	(-70 to -60) dB	0.06 dB	
	(-60 to -50) dB	0.055 dB	
	(-50 to -40) dB	0.054 dB	
	(-40 to -30) dB	0.045 dB	
	(-30 to -20) dB	0.039 dB	
	(-20 to -10) dB	0.034 dB	
	(-10 to 0) dB	0.029 dB	

Electrical – RF/Microwave

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
Tuned RF Absolute Power – Measure	100 kHz to 2 MHz		Comparison to Agilent E4440A PSA Spectrum Analyzer
	(-127 to -120) dB	1.1 dB	
	(-120 to -110) dB	0.62 dB	
	(-110 to -100) dB	0.21 dB	
	(-100 to -90) dB	0.13 dB	
	(-90 to -80) dB	0.12 dB	
	(-80 to -70) dB	0.12 dB	
	(-70 to -60) dB	0.11 dB	
	(-60 to -50) dB	0.1 dB	
	(-50 to -40) dB	0.1 dB	
	(-40 to -30) dB	0.1 dB	
	(-30 to -20) dB	0.097 dB	
	(-20 to -10) dB	0.095 dB	
	(-10 to 0) dB	0.094 dB	
	(2 to 10) MHz		
	(-127 to -120) dB	0.42 dB	
	(-120 to -110) dB	0.19 dB	
	(-110 to -100) dB	0.13 dB	
	(-100 to -90) dB	0.12 dB	
	(-90 to -80) dB	0.12 dB	
	(-80 to -70) dB	0.11 dB	
	(-70 to -60) dB	0.11 dB	
	(-60 to -50) dB	0.11 dB	
	(-50 to -40) dB	0.1 dB	
	(-40 to -30) dB	0.1 dB	
	(-30 to -20) dB	0.099 dB	
	(-20 to -10) dB	0.097 dB	
	(-10 to 0) dB	0.095 dB	

Electrical – RF/Microwave

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
Tuned RF Absolute Power – Measure	10 MHz to 3.05 GHz		Comparison to Agilent E4440A PSA Spectrum Analyzer
	(-127 to -120) dB	0.42 dB	
	(-120 to -110) dB	0.19 dB	
	(-110 to -100) dB	0.13 dB	
	(-100 to -90) dB	0.12 dB	
	(-90 to -80) dB	0.12 dB	
	(-80 to -70) dB	0.11 dB	
	(-70 to -60) dB	0.11 dB	
	(-60 to -50) dB	0.11 dB	
	(-50 to -40) dB	0.1 dB	
	(-40 to -30) dB	0.1 dB	
	(-30 to -20) dB	0.099 dB	
	(-20 to -10) dB	0.097 dB	
	(-10 to 0) dB	0.095 dB	
	(3.05 to 6.6) GHz		
	(-127 to -120) dB	0.42 dB	
	(-120 to -110) dB	0.2 dB	
	(-110 to -100) dB	0.14 dB	
	(-100 to -90) dB	0.13 dB	
	(-90 to -80) dB	0.13 dB	
	(-80 to -70) dB	0.12 dB	
	(-70 to -60) dB	0.12 dB	
	(-60 to -50) dB	0.12 dB	
	(-50 to -40) dB	0.12 dB	
	(-40 to -30) dB	0.11 dB	
	(-30 to -20) dB	0.11 dB	
	(-20 to -10) dB	0.11 dB	
	(-10 to 0) dB	0.11 dB	

Electrical – RF/Microwave

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
Tuned RF Absolute Power – Measure	(6.6 to 13.2) GHz		Comparison to Agilent E4440A PSA Spectrum Analyzer
	(-127 to -120) dB	0.68 dB	
	(-120 to -110) dB	0.34 dB	
	(-110 to -100) dB	0.15 dB	
	(-100 to -90) dB	0.13 dB	
	(-90 to -80) dB	0.13 dB	
	(-80 to -70) dB	0.12 dB	
	(-70 to -60) dB	0.12 dB	
	(-60 to -50) dB	0.12 dB	
	(-50 to -40) dB	0.12 dB	
	(-40 to -30) dB	0.11 dB	
	(-30 to -20) dB	0.11 dB	
	(-20 to -10) dB	0.11 dB	
	(-10 to 0) dB	0.11 dB	
	(13.2 to 18) GHz		
	(-127 to -120) dB	1.1 dB	
	(-120 to -110) dB	0.62 dB	
	(-110 to -100) dB	0.22 dB	
	(-100 to -90) dB	0.14 dB	
	(-90 to -80) dB	0.13 dB	
	(-80 to -70) dB	0.13 dB	
	(-70 to -60) dB	0.12 dB	
	(-60 to -50) dB	0.12 dB	
	(-50 to -40) dB	0.12 dB	
	(-40 to -30) dB	0.11 dB	
	(-30 to -20) dB	0.11 dB	
	(-20 to -10) dB	0.11 dB	
	(-10 to 0) dB	0.11 dB	

Electrical – RF/Microwave

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
Tuned RF Absolute Power – Measure	(18 to 26.5) GHz (-127 to -120) dB (-120 to -110) dB (-110 to -100) dB (-100 to -90) dB (-90 to -80) dB (-80 to -70) dB (-70 to -60) dB (-60 to -50) dB (-50 to -40) dB (-40 to -30) dB (-30 to -20) dB (-20 to -10) dB (-10 to 0) dB	1.8 dB 1.2 dB 0.53 dB 0.22 dB 0.19 dB 0.19 dB 0.18 dB 0.18 dB 0.18 dB 0.18 dB 0.18 dB 0.18 dB 0.17 dB	Comparison to Agilent E4440A PSA Spectrum Analyzer
Phase Noise – Measure	1 MHz to 3 GHz (3 to 6.6) GHz (6.6 to 22) GHz (22 to 26.5) GHz	3.9 dB 4.2 dB 4.4 dB 4.7 dB	Comparison to Agilent E4440A PSA Spectrum Analyzer
Spectral Analysis – Measure	3 Hz to 3 GHz (3 to 6.6) GHz (6.6 to 13.2) GHz (13.2 to 22) GHz (22 to 26.5) GHz	0.93 dB 1.9 dB 3 dB 3.1 dB 3.4 dB	Comparison to Agilent E4440A PSA Spectrum Analyzer
Sine-wave Flatness	9 kHz to 6 GHz	1.7 % of reading	Comparison to Agilent E4418B Power Meter, Agilent E9304A Power Sensor

Length – Dimensional Metrology

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
Calipers ^{1,4}	Up to 60 in	$(5 + 8L) \mu\text{in}$	Comparisons to Gage Blocks
Bore Gages ^{4,7} 2-point	(0.24 to 9) in	$(4.3 + 4.7L) \mu\text{in}$	Comparison to Horizontal Measuring Machine
3-point	(0.24 to 9) in	$(85 + 7L) \mu\text{in}$	Cylindrical Rings

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Length – Dimensional Metrology

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
Crimp Tools ¹ Crimp Height	(0.011 to 1) in	87 µin	Comparisons to Crimp Height Micrometer
Limit Gaging (Size)	(0.011 to 1) in	224 µin	Plug Gages
External Diameters ⁴	(0.002 to 12) in	(3 + 3L) µin	Comparison to P&W Labmaster®
Feeler/Thickness Gages	Up to 1 in	8 µin	Comparison to Horizontal Measuring System
Gage Blocks ⁴	(0.004 to 20) in	(1.4 + 1.4L) µin	Comparison to Master Blocks, Universal Length Measuring Machine
Graduated Scales	Up to 72 in	0.001 6 in	Comparison to Master Graduated Scale, Eye Loupe
Height Measuring Equipment ⁴	(0.01 to 8) in (8 to 40) in	(17 + 3.4L) µin (15 + 4.3L) µin	Comparison to Gage Blocks, Surface Plate
Indicators ^{1,4}	(0.000 1 to 6) in	(5 + 4L) µin	Comparison to Horizontal Measuring Machine
Internal Diameters ⁴	(0.040 to 13) in	(3 + 3L) µin	Comparison to P&W Labmaster®
Outside Micrometers ^{1,4} Length	Up to 60 in	(5 + 8L) µin	Comparison to Gage Blocks
Flatness	(0 to 50) µin	4 µin	Optical Parallel
Micrometers – Depth ¹	Up to 12 in	90 µin	Comparison to Gage Blocks
Micrometers – Inside ⁴	(0.5 to 8) in (8 to 24) in	(6 + 1.7L) µin (7 + 3L) µin	Comparison to Mitutoyo LH 600D Linear Height Gage, Universal Length Measuring Machine
Length Standards ⁴	(1 to 24) in	(3.4 + 3.5L) µin	Comparison to Mitutoyo LH 600D Linear Height Gage, Universal Length Measuring Machine

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Length – Dimensional Metrology

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
Micrometer Head Travel ⁴	Up to 4 in	$(8 + 4L) \mu\text{in}$	Comparison to Horizontal Measuring System-Gage Blocks
Pin Gages Outside Diameter	(0.004 to 1) in	36 μin	Direct Measure using Laser Micrometer
Profilometers	Up to 500 μin	1.1 % of nominal + 0.7 μin	Comparison to Master Patch
Surface Roughness	Up to 118 μin (118.1 to 500) μin	1 % of nominal + 0.5 μin 1 % of nominal + 0.6 μin	Comparison to Profilometer, Master Patch
Surface Plates ^{1,4} Overall Flatness Local Area Flatness (Repeat Readings)	Up to 168.4 inDL Up to 0.001 in	$1.7 \sqrt{DL} + 5.5 \mu\text{in}$ 32 μin	In accordance with Fed Spec GGG-P-463 utilizing Electronic Levels Supramess Indicator
Thickness Gages ^{1,7} Dial Digital	Up to 1 in Up to 1 in	410 μin 44 μin	Comparison to Gage Blocks
Thread Plugs ^{1,4} Pitch Diameter Major Diameter	Up to 8 in Pitch (0.2 to 5) mm Up to 8 in Pitch 90 – 4 TPI	$(87 + 1.9L) \mu\text{in}$ 43 μin	Comparisons to Horizontal Measuring Machine, Thread Wires
Adjustable Thread Rings Pitch Diameter	Up to 4 in	See Footnote 8	Tactile Fit to Master Thread Setting Plug
Video Measuring Machines ^{1,4} X-Y Linearity	Up to 12 in	$(32 + 4.1L) \mu\text{in}$	Comparison to Glass Scales
Coordinate Measuring Machines ^{1,4} X-Y-Z Linearity Volumetric Repeatability	(0.1 to 20) in (1 to 24) in (0.5 to 2) in	$(22 + 3L) \mu\text{in}$ 66 μin 45 μin	Comparisons to Gage Blocks Ball Bar CMM Sphere

Mass and Mass Related

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
Force Measuring Equipment (Tension and Compression)	(1 to 250) lbf	0.017 % of reading	Comparison to Deadweights
Torque Measuring Instruments ¹	(20 to 80) ozf·in (5 to 50) lbf·in (50 to 400) lbf·in (400 to 1 000) lbf·in (80 to 250) lbf·ft (250 to 600) lbf·ft (600 to 1 000) lbf·ft	1 % of reading 0.4 % of reading 0.4 % of reading 0.4 % of reading 0.4 % of reading 0.4 % of reading 0.4 % of reading	Comparison to Torque Calibrator
Torque Angle ¹	45° 90° 135° 180° 360°	0.35° 0.35° 0.35° 0.35° 0.35°	Comparison to Torque Angle Fixture
Balances ^{1,5} Avoirdupois	(0.07 to 0.18) oz (0.18 to 1.8) oz 1.8 oz to 58 lb	0.13 mg 0.001 7 % of reading 0.000 6 % of reading	Class S Weights and internal calibration procedure utilized in the calibration of the weighing device.
SI (metric)	(2 to 5) g (5 to 50) g 50 g to 26 kg	0.13 mg 0.001 7 % of reading 0.000 6 % of reading	
Balances ^{1,5} Avoirdupois	Up to 0.018 oz (0.018 to 0.2) oz (0.2 to 0.4) oz (0.4 to 0.7) oz 0.7 oz to 13 lb	12 µg 40 µg 60 µg 90 µg 0.000 3% of reading	ASTM E617 Class 1 Weights and internal calibration procedure utilized in the calibration of the weighing device.
SI (metric)	Up to 500 mg 500 mg to 5 g (5 to 10) g (10 to 20) g 20 g to 6 kg	12 µg 40 µg 60 µg 90 µg 0.000 3% of reading	
Scales ^{1,5} Avoirdupois	(50 to 600) lb	0.012 % of reading	NIST Class F Weights and internal calibration procedure utilized in the calibration of the weighing device.
SI (metric)	(22 to 272) kg	0.012 % of reading	

Mass and Mass Related

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
Absolute Pressure – Source (Pneumatic)	Up to 25 psia (25 to 500) psia	0.001 9 psi 0.007 % of reading + 0.001 psi	Comparison to Ruska 7250xi Pressure Controller/Calibrator
Absolute and Gauge Pressure – Source (Pneumatic)	Up to 125 psia (125 to 250) psia (250 to 500) psia (500 to 1 015) psia Up to 110 psig (110 to 235) psig (235 to 485) psig (485 to 1 000) psig	0.13 psia 0.25 psia 0.5 psia 1 psia 0.13 psig 0.25 psig 0.5 psig 1 psig	Comparison to Mensor CPC6050 Pressure Controller with Modules
Gauge Pressure – Source (Pneumatic)	(-15 to 25) psig (25 to 500) psig	0.001 7 psi 0.007 % of reading	Comparison to Ruska 7250xi Pressure Controller/Calibrator
Gauge Pressure – Source (Hydraulic)	Up to 1 500 psig (1 500 to 3 000) psig	0.36 psi 0.023 % of reading	Comparison to Fluke RPM4-E-DWT Electronic Deadweight Tester
Gauge Pressure – Source (Hydraulic)	(3 000 to 10 000) psig (10 000 to 30 000) psig	0.01 % of reading + 0.25 psi 35 psi	Comparison to Pressure Calibrator
Mass Flow Devices (Gas)	(5 to 30 000) sccm	0.93 % of reading	Comparison to Mesa Flow System
Mass Flow Devices (Gas)	(0.1 to 10) slpm (10 to 680) slpm	0.23 % of reading 0.15 % of reading	Comparison to Bell Prover
Liquid Flow	(0.001 to 47) gpm (0.004 to 178) lpm (0.4 to 23 500) pph	0.1 % of reading 0.1 % of reading 0.1 % of reading	Comparison to Liquid Ballistic Prover

Thermodynamic

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
Temperature Measuring Instruments ¹ (Probes, Thermometers, etc.)	(0 to 100) °C	0.038 °C	Comparison to Hart 5609A PRT, Digital Readout, Drywell
Temperature – Measure ¹	(-195 to 0) °C (0 to 420) °C (420 to 600) °C	0.012 °C 0.025 °C 0.036 °C	Comparison to Hart 56A PRT, Digital Readout
Temperature – Source/Measure ¹	(-200 to 1 372) °C	1.3 °C	Comparison to Process Calibrator, Thermocouple Probe
Temperature – Source/Measure ¹	(0 to 400) °C	0.13 % of reading + 8.4 mK	Comparison to Process Calibrator, RTD
Infrared Temperature Measuring Equipment	(-15 to 0) °C (0 to 50) °C (50 to 100) °C	0.79 °C 0.53 °C 0.67 °C	Comparison to Blackbody Source (flat plate) $\epsilon = (0.9 \text{ to } 1)$, $\lambda = (8 \text{ to } 14) \mu\text{m}$
Infrared Temperature Measuring Equipment	(100 to 120) °C (120 to 200) °C (200 to 350) °C (350 to 500) °C	0.75 °C 0.97 °C 1.7 °C 2.2 °C	Comparison to Blackbody Source (flat plate) $\epsilon = (0.9 \text{ to } 1)$, $\lambda = (8 \text{ to } 14) \mu\text{m}$
Relative Humidity – Measure ¹	(10 to 30) °C (20 to 90) %RH	1.3 %RH	Comparison to Vaisala HMI41/HMP46 Temperature/Humidity Indicator/Probe
Relative Humidity – Source/Measure ¹	(10 to 65) %RH (65 to 95) %RH	1.1 %RH 1.1 %RH	Comparison to Rotronic HF532 Indicator with Probe
Temperature Uniformity Surveys ¹	(-200 to 0) °C (0 to 1 093) °C (1 093 to 1 344) °C	1.2 °C 1.3 °C 2.1 °C	Per AMS 2750 and BAC 5621 using Datalogger and SLE Thermocouples.

Time and Frequency

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
AC Duty Cycle – Source ¹ Square Wave: < 3.3 Vp-p Freq: 0.01 Hz to 100 kHz	(1 to 10) % Duty Cycle 10 μ S to 100 s (10 to 49) % Duty Cycle 10 μ S to 100 s 50 % Duty Cycle 10 μ S to 100 s	0.62 % of reading + 78 ns 0.4 % of reading + 78 ns 0.02 % of reading + 78 ns	Comparison to Fluke 5522A Multiproduct Calibrator
AC Duty Cycle – Source ¹ Square Wave: < 3.3 Vp-p Freq: 0.01 Hz to 100 kHz	(51 to 90) % Duty Cycle 10 μ S to 100 s (90 to 99) % Duty Cycle 10 μ S to 100 s	0.04 % of reading + 78 ns 0.62 % of reading + 78 ns	Comparison to Fluke 5522A Multiproduct Calibrator
Frequency – Reference	10 MHz	3.7 pHz/Hz	Comparison to Pendulum GPS-89 GPS Frequency Standard
Frequency – Measure ¹	1 Hz to 10 kHz 10 kHz to 10 MHz (10 to 225) MHz 225 MHz to 26.5 GHz	19 pHz/Hz + 4.5 μ Hz 19 pHz/Hz + 18 μ Hz 19 pHz/Hz + 0.64 mHz 0.21 μ Hz/Hz + 0.12 Hz	Comparison to Agilent 53132A Universal Counter, Pendulum GPS-89 GPS Frequency Standard, Keysight PSA E4440A Spectrum Analyzer
Period – Measure	(1 to 100) s	45 μ s	Comparison to Agilent 53132A Universal Counter, Pendulum GPS-89 GPS Frequency Standard
Rise Time – Source	350 ps	64 ps	Comparison to Tektronix PG509 Rise Time Pulse Generator
Rise Time – Measure	17.5 ps 20 GHz	12 ps	Comparison to Agilent 86100A Wide-bandwidth Oscilloscope, Agilent 83478A Plug-in
Stopwatches, Timers ^{1,4}	Up to 86 400 s (1 d)	31 ms/d	Comparison to Helmut Klein TM-4500 Timometer

Time and Frequency

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
Non-contact Tachometers ^{1,4}	Up to 60 000 rpm	0.000 23% of reading + 0.001 2 rpm	Comparison to Keysight 33250A Waveform Generator

DIMENSIONAL MEASUREMENT

2 Dimensional

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
Angle Measurements ⁴	(0.25 to 60)°	2.48"	Comparisons to Gage Blocks, Gage Amplifier, Sine Bar
Surface Finish Analysis	Up to 118 µin (118.1 to 500) µin	1 % of nominal + 0.05 µin 1 % of nominal + 0.6 µin	Comparison to Profilometer, Master Patch

3 Dimensional

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
3D Dimensional Inspection ²	X axis: 16 in Y axis: 18 in Z axis: 14 in	(209 + 1.2L) µin	Coordinate Measuring Machine utilized as the reference standard for contact Dimensional Inspection.
3D Dimensional Inspection ²	X axis: 12 in Y axis: 8 in Z axis: 4 in	(44 + 1L) µin	Vision System utilized as the reference standard for non-contact Dimensional Inspection.

Calibration and Measurement Capability (CMC) is expressed in terms of the measurement parameter, measurement range, expanded uncertainty of measurement and reference standard, method, and/or equipment. The expanded uncertainty of measurement is expressed as the standard uncertainty of the measurement multiplied by a coverage factor of 2 ($k=2$), corresponding to a confidence level of approximately 95%.

Notes:

1. On-site calibration service is available for this parameter, since on-site conditions are typically more variable than those in the laboratory, larger measurement uncertainties are expected on-site than what is reported on the accredited scope
2. The uncertainties shown are for the most favorable conditions. There is an increase in uncertainty that corresponds to the laboratory's AC voltage and current uncertainties at frequencies other than the ones shown. Power factors (PF) other than the one shown contribute to the power uncertainty. PF is related to the cosine of phase. Therefore, uncertainties track the laboratory's phase uncertainty closely at PF near one but are magnified heavily as PF approaches zero. The lab may also report reactive power, apparent power, and power factor under this accreditation. If needed, contact the laboratory for more information regarding uncertainties at frequency and power factor combinations other than the ones shown.
3. The stated uncertainty is the laboratory's ability to source a fast rise pulse that is approximately 250 ps. In the typical application of measuring rise time of an oscilloscope, this value is one of the contributing factors, but other factors are derived from the DUT.
4. L = length in inches; rpm = revolutions per minute; d = day.
5. The CMC for scales and balances is highly dependent upon the resolution of the unit under test. The CMC presented here does not include the resolution of the unit under test. The resolution will be included in the reported measurement uncertainty at the time of calibration.
6. The fixed value stated on the Scope is an approximate value.
7. $0.6R$ (where R is the resolution of the unit under calibration) will be added to the Measurement Uncertainty (MU) at the time of calibration.
8. The tactile fit of an adjustable thread ring to a thread-setting plug is not a measurement of pitch diameter. The uncertainty for this pitch diameter setting is based on the contributors associated with the thread setting plug and environmental contributors only.
9. Unless otherwise specified in the far-right column, the calibration procedure utilized by the laboratory was written and validated internally.
10. This location is part of a Multi-site Organization whose legal entity name is Transcat, Inc.



Jason Stine, Vice President

